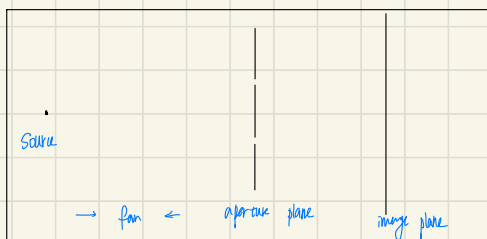




diffraction / interference pattern of light passing through apertures
 light from a distant source
 plane with apertures
 an image plane, on which diffraction pattern is shown

assume light is an oscillating Electrical Magnetic (EM) field
 { monochromatic (only one frequency of light - those being diffracted)

distance of the image plane determines near-field / far-field diffraction
 measure distance relative to the wavelength

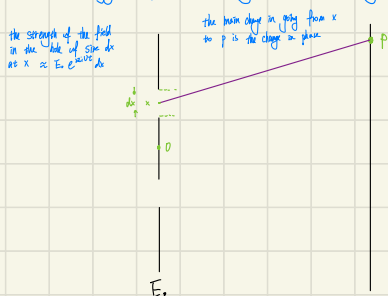


faraway source means that the aperture plane is a wavefront (light comes in as a plane wave)
 we have the same phase at all points of the aperture plane

represent the light on the plane by a time-oscillating electric field $E_0 e^{2\pi i \nu t}$ (assume the light is a single frequency)
 strength of the field, E_0 on the aperture plane

what's the electrical field at a point p on the imaging plane
 the wave gets to p along diffraction paths, how do they add up? (typically Huygens principle)

approach with Huygens principle: every aperture can be regarded as a new source (not modern view)



phase change in traveling a distance r from x to p : $\frac{2\pi r}{\lambda}$ where λ is the wavelength
 the field at p due to field at x is $dE = E_0 \cdot e^{2\pi i \nu t} \cdot e^{-2\pi i r / \lambda} \cdot dx$

total field: $\int_{\text{apertures}} E_0 \cdot e^{2\pi i \nu t} \cdot e^{-2\pi i r / \lambda} dx$ (r depends on x)

$$= E_0 \cdot e^{i 2\pi i r} \int_{\text{apertures}} e^{-i 2\pi i x/\lambda} dx$$

↓ you see the magnitude of $|E|$

$$\begin{aligned} \text{what's seen} &= E_0 \int_{\text{apertures}} e^{-i 2\pi i x/\lambda} dx \\ &= E_0 \int_{\text{apertures}} e^{-i 2\pi i (r - x \sin \theta)/\lambda} dx \\ &= E_0 e^{-i 2\pi i r/\lambda} \int_{\text{apertures}} e^{i 2\pi i x \sin \theta/\lambda} dx \\ p = \sin \theta/\lambda &= E_0 e^{-i 2\pi i r/\lambda} \int_{\text{apertures}} e^{i 2\pi i x p} dx \\ &= E_0 e^{-i 2\pi i r/\lambda} \int_{-\infty}^{\infty} A(x) e^{i 2\pi i x p} dx \\ &= E_0 e^{-i 2\pi i r/\lambda} (\mathcal{F}^* A)(p) \quad (= E_0 e^{-i 2\pi i r/\lambda} (\mathcal{F} A)(-p)) \end{aligned}$$

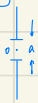
Fraunhofer approximation:
when $r \gg x$, $r - x \sin \theta \approx r$
(far field diffraction)



introduce aperture function
 $A(x) = \begin{cases} 1 & \text{if } x \in \text{aperture} \\ 0 & \text{if } x \text{ is opaque} \end{cases}$

Under far field diffraction, the intensity of light (what you see) is the magnitude of the Fourier Transform of the aperture function

eg. Single-slit diffraction



$$A(x) = T_a(x)$$

$$(\mathcal{F} A)(p) = a \cdot \text{sinc}(-ap) = a \text{sinc}\left(\frac{a \sin \theta}{\lambda}\right)$$

eg. delta aperture

$$A(x) = \delta(x)$$

$$(\mathcal{F} A)(p) = 1 \quad \text{uniformly illuminated}$$

eg. Young's double slit



$$A(x) = T_a(x + \frac{b}{2}) + T_a(x - \frac{b}{2})$$

$$a \text{sinc}(ap) \cos(bap) \quad p = \sin \theta/\lambda$$